

**Product Summary**

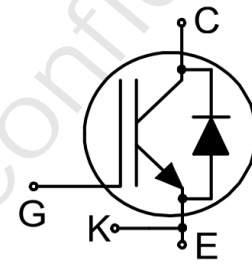
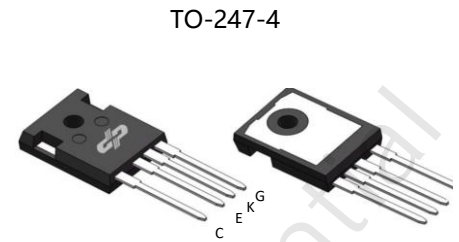
Part #	$V_{CE}$	$I_C$	$V_{CEsat}, T_{vj}=25^{\circ}C$
DP75N65JBDSI2	650V	75A	1.65V

**Features**

- Uses advanced FS IGBT technology
- Excellent conduction and switching loss
- Excellent stability and uniformity
- Fast and soft antiparallel diode

**Applications**

- Induction converters
- Uninterruptible power supplies
- Home Appliances


**Package Marking and Ordering Information**

Part #	Marking	Package	Packing
DP75N65JBDSI2	75N65JBDSI2	TO-247-4	Tube


**Absolute Maximum Ratings**

Parameter	Symbol	Value	Unit
Collector-Emitter voltage	$V_{CE}$	650	V
Continuous collector current	$I_C$	150	A
$T_C = 25^{\circ}C$		75	
$T_C = 100^{\circ}C$			
Pulsed collector current ( $T_C = 25^{\circ}C$ , $t_p$ limited by $T_{jmax}$ )	$I_{D\ pulse}$	300	A
Turn off safe operating area $V_{CE} \leq 650V$ , $T_{vj} \leq 175^{\circ}C$	-	300	A
Diode forward current	$I_F$	150	A
$T_C = 25^{\circ}C$		75	
$T_C = 100^{\circ}C$			
Diode pulsed current ( $T_C = 25^{\circ}C$ , $t_p$ limited by $T_{jmax}$ )	$I_{F\ pulse}$	300	A
Gate-emitter voltage	$V_{GE}$	$\pm 30$	V
Power dissipation ( $T_C = 25^{\circ}C$ )	$P_{tot}$	469	W
Operating junction temperature	$T_j, T_{stg}$	-40...+175	$^{\circ}C$
Storage temperature	$T_j, T_{stg}$	-55...+150	$^{\circ}C$

**Thermal Resistance**

Parameter	Symbol	Max	Unit
IGBT thermal resistance, junction case. Max	$R_{thJC}$	0.32	°C/W
Diode thermal resistance, junction case. Max	$R_{thJC}$	0.4	
Thermal resistance, junction – ambient. Max	$R_{thJA}$	40	

**Electrical Characteristic (at  $T_j = 25\text{ }^\circ\text{C}$ , unless otherwise specified)**

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		

**Static Characteristic**

Collector-emitter breakdown voltage	$V_{(BR)CES}$	650	-	-	V	$V_{GE}=0V, I_C=250\mu A$
Collector-emitter saturation voltage	$V_{CEsat}$	-	1.65	2	V	$V_{GE} = 15V, I_C = 75A$
		-	2	-		$T_{vj}=25^\circ\text{C}$
		-	2.2	-		$T_{vj}=150^\circ\text{C}$
Diode forward voltage	$V_F$	-	1.55	2	V	$V_{GE} = 0V, I_F = 75A$
		-	1.5	-		$T_{vj}=175^\circ\text{C}$
Gate-emitter threshold voltage	$V_{GE(th)}$	4.2	4.8	5.5	V	$V_{GE} = V_{CE}, I_C = 1mA$
Zero gate voltage collector current	$I_{CES}$	-	-	1	$\mu A$	$V_{CE}=650V, V_{GS}=0V$
		-	100	-		$T_{vj}=150^\circ\text{C}$
Gate-emitter leakage current	$I_{GES}$	-	-	100	nA	$V_{CE} = 0V, V_{GE} = \pm 30V$

**Dynamic Characteristic**

Input Capacitance	$C_{ies}$	-	6542	-	pF	$V_{CE} = 25V, V_{GE} = 0V,$ $f = 100KHz$
Output Capacitance	$C_{oes}$	-	207	-		
Reverse Transfer Capacitance	$C_{res}$	-	48	-		
Gate Total Charge	$Q_g$	-	193	-	nC	$V_{CC} = 520V, I_C = 10A,$ $V_{GE} = 15V$
Gate-Source charge	$Q_{ge}$	-	48	-		
Gate-Drain charge	$Q_{gc}$	-	45	-		
Turn-on delay time	$t_{d(on)}$	-	44	-	ns	$T_{vj} = 25^\circ C,$ $V_{CC} = 400V, I_C = 75A,$ $V_{GE} = 15.0V,$ $R_G = 10.0\Omega$
Rise time	$t_r$	-	92	-		
Turn-off delay time	$t_{d(off)}$	-	182	-		
Fall time	$t_f$	-	108	-		
Turn-on energy	$E_{on}$	-	2.0	-	mJ	
Turn-off energy	$E_{off}$	-	2.0	-		
Turn-on delay time	$t_{d(on)}$	-	42	-	ns	$T_{vj} = 175^\circ C,$ $V_{CC} = 400V, I_C = 75A,$ $V_{GE} = 15.0V,$ $R_G = 10.0\Omega$
Rise time	$t_r$	-	94	-		
Turn-off delay time	$t_{d(off)}$	-	202	-		
Fall time	$t_f$	-	124	-		
Turn-on energy	$E_{on}$	-	2.2	-	mJ	
Turn-off energy	$E_{off}$	-	2.3	-		

**Diode Characteristic**

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Diode peak reverse recovery current	$I_{rrm}$	-	15	-	A	$T_{vj} = 25^\circ C,$ $V_R = 400V,$ $I_F = 10.0A,$ $diF/dt = 200A/\mu s$
Body Diode Reverse Recovery Time	$t_{rr}$	-	178	-	ns	
Body Diode Reverse Recovery Charge	$Q_{rr}$	-	1887	-	nC	

**Typical Performance Characteristics**

Fig 1: Output Characteristics

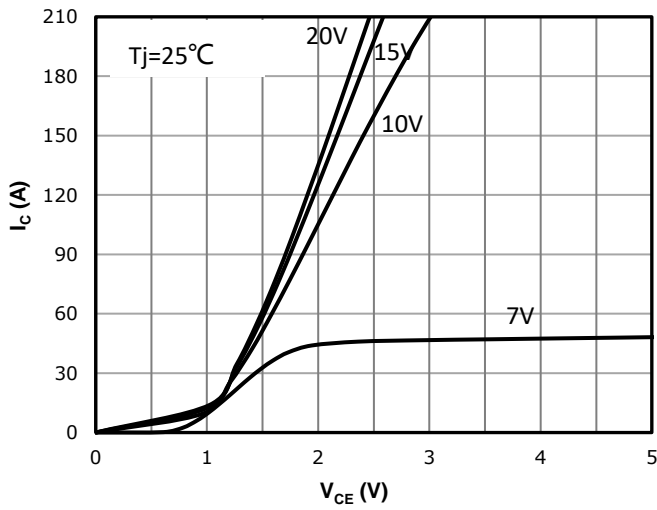


Fig 2: Output Characteristics

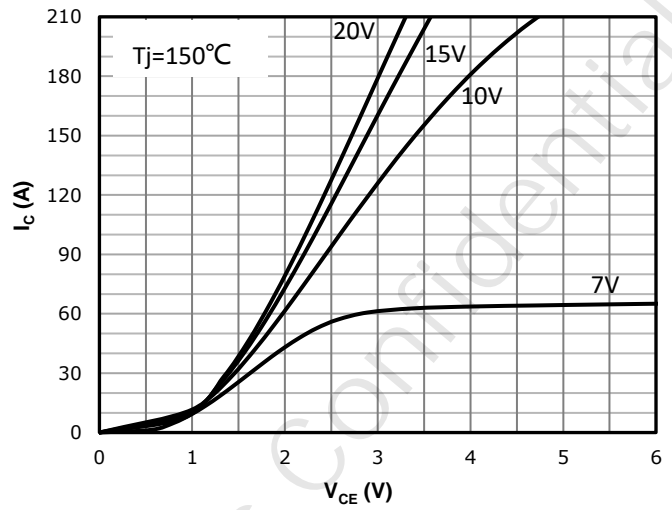


Fig 3: Transfer Characteristics

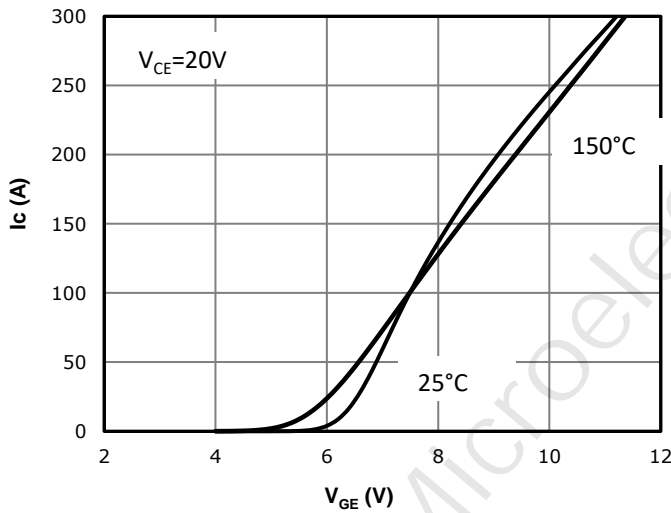


Fig 4: Typical collector-emitter voltage

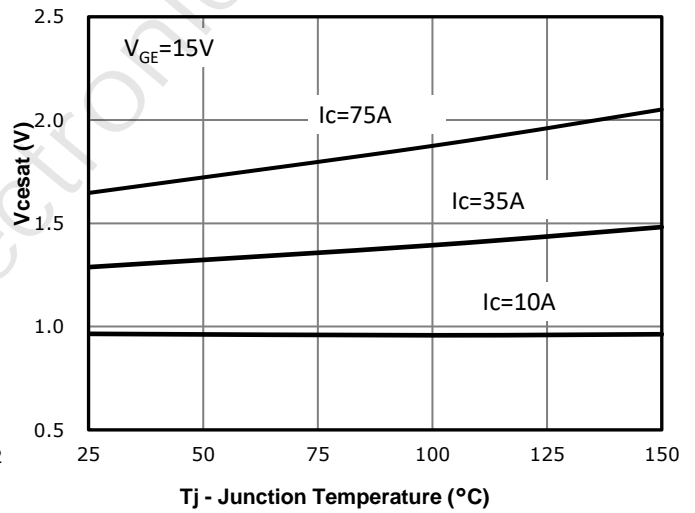


Fig 5: Gate Charge Characteristics

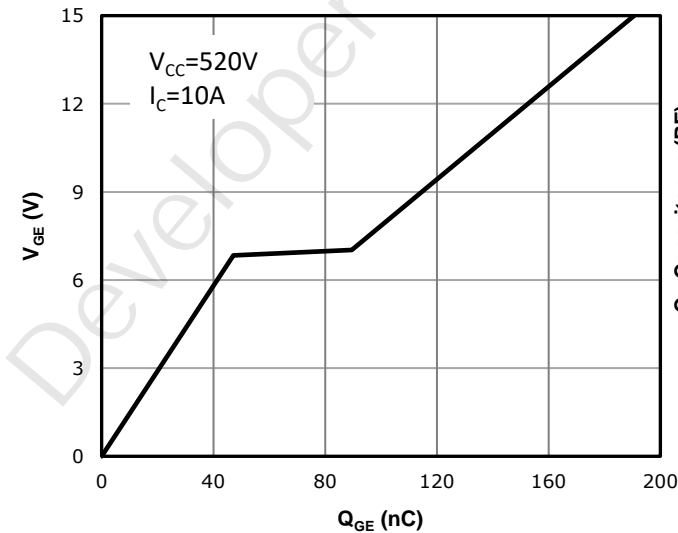


Fig 6: Capacitance Characteristics

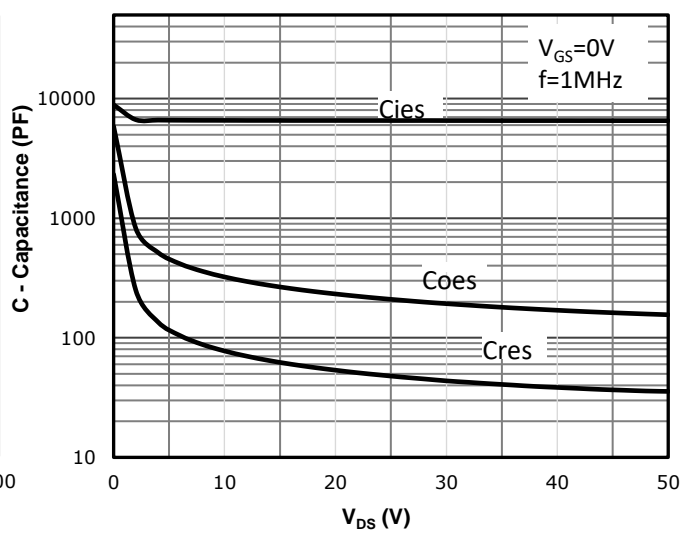


Fig 7: Typical switching energy losses

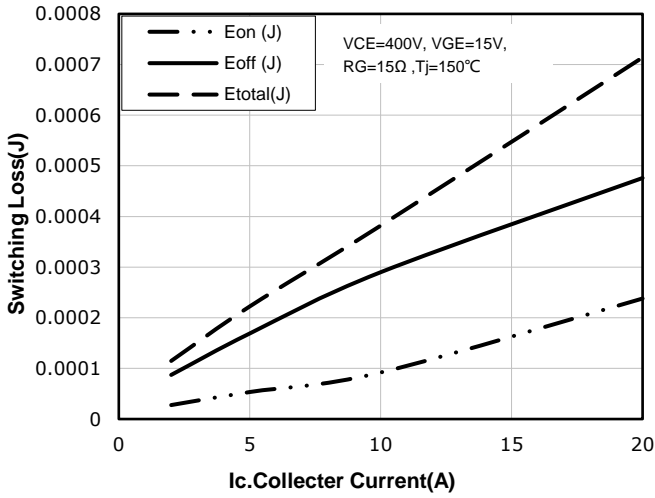


Fig 8: Typical switching times as a function of gate resistor

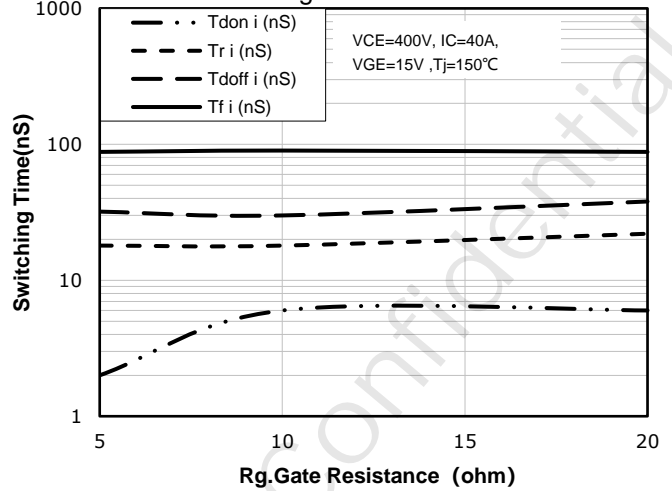


Fig 9: Typical switching energy losses as a function of gate resistor

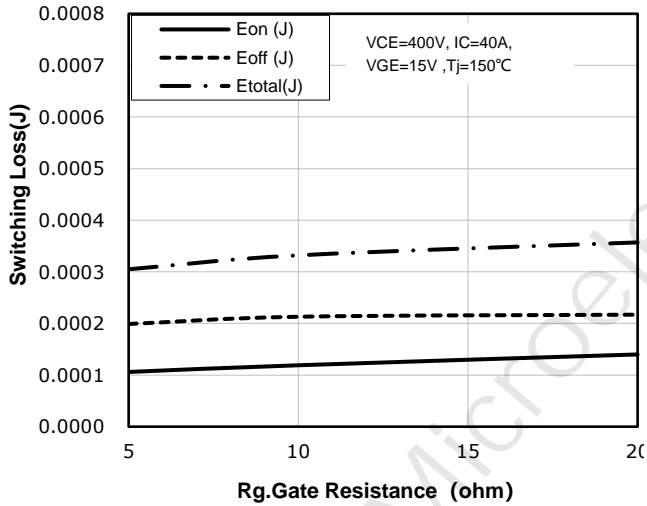


Fig 10: Typical switching energy losses as a function of collector emitter voltage

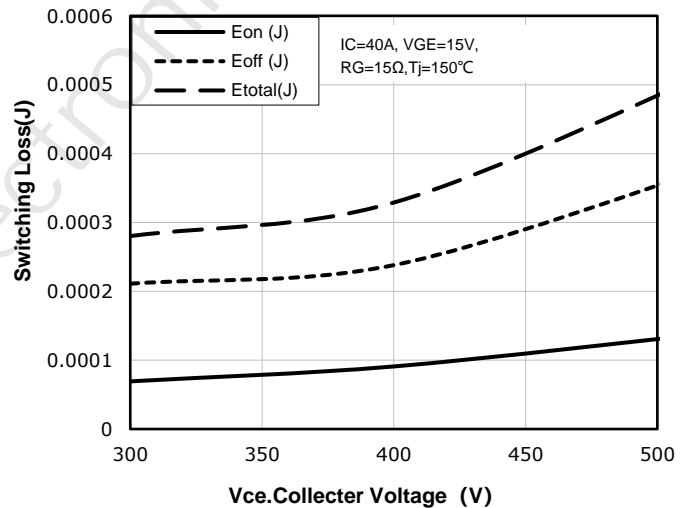


Fig 11: Typical switching times as a function of junction temperature

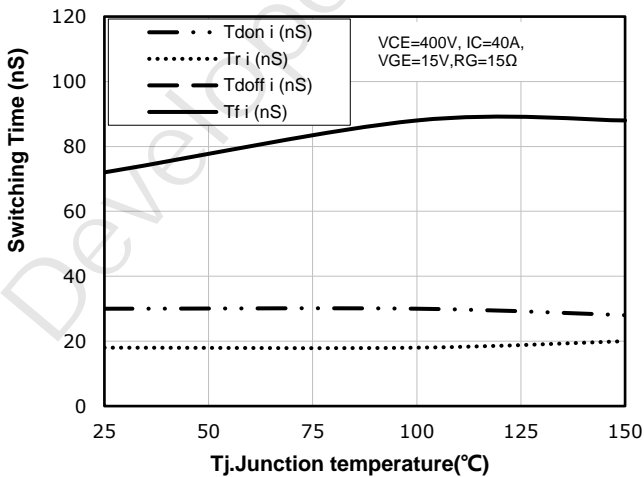


Fig 12: Typical switching energy losses as a function of junction temperature

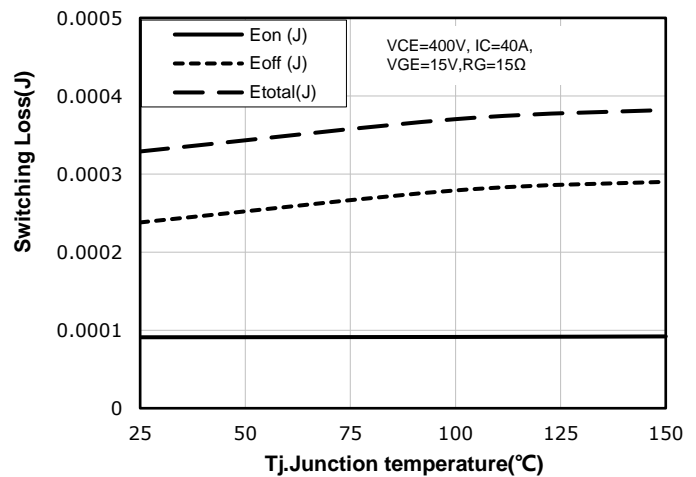
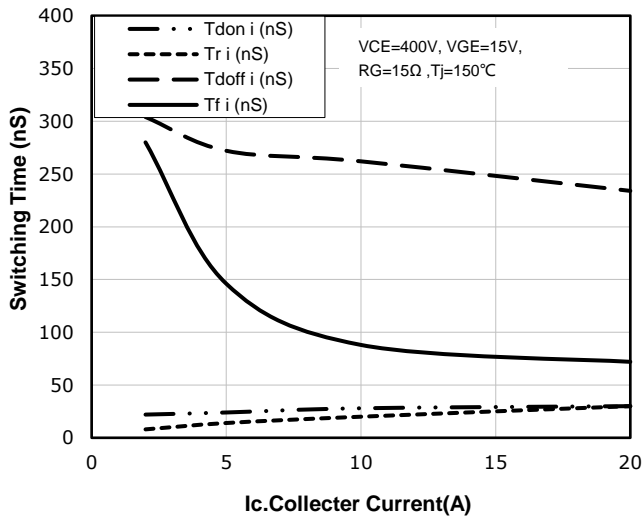
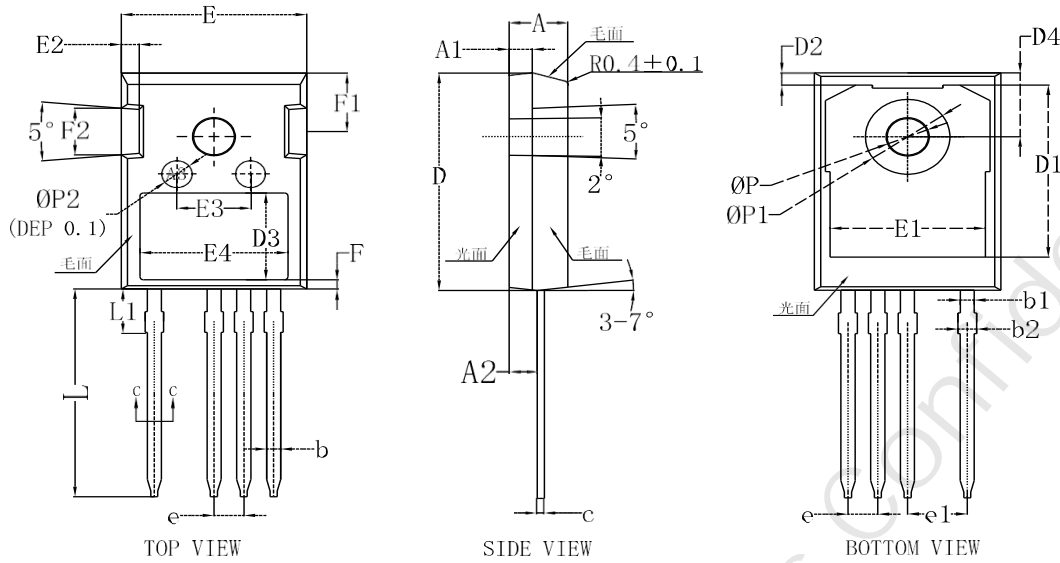


Fig 13: Typical switching times

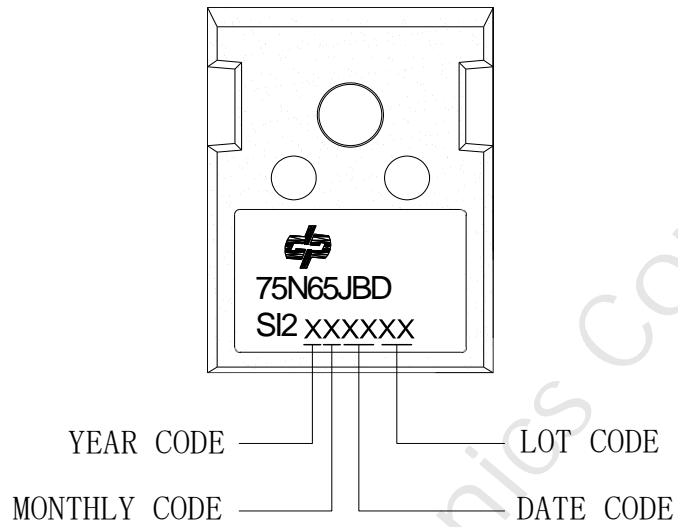


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**Package Outline: TO247-4L**


Symbol	Dimensions In Millimeters		
	MIN	NOM	MAX
A	4.90	5.00	5.10
A1	1.90	2.00	2.10
A2	2.31	2.41	2.51
b	1.15	1.20	1.25
b1	1.15	1.20	1.25
b2	1.20	1.30	1.40
b3	1.20	1.25	1.30
c	0.55	0.60	0.65
c1	0.60	0.62	0.64
D	20.90	21.00	21.10
D1	16.45	16.55	16.65
D2	1.07	1.17	1.27
D3	8.15	8.20	8.25
D4	6.05	6.15	6.25
E	15.70	15.70	15.90
E1	13.16	13.26	13.36
E2	2.40	2.50	2.60
E3	6.10	6.20	6.30
E4	12.70	12.80	12.90
F	0.75	0.85	0.90
F1	5.70	5.80	5.90
F2	4.90	5.00	5.10
e	2.54 BSC		
e1	5.08 BSC		
L	19.72	19.92	20.12
L1	4.03	4.13	4.23
ΦP	3.50	3.60	3.70
ΦP1	7.09	7.19	7.29
ΦP2	2.40	2.50	2.60

**Part Marking Information**



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## Revision History

Revision	Major changes
1.1	Release for initial version

## 重要声明 Important Notice

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